

Study Group C37.011 met on April 27<sup>th</sup> with 22 members and 33 guests present.

The content of the last two revisions of 2005 and 2011 were presented. Several reasons support a new revision of C37.011:

- To align the content with the latest revisions of IEEE Std C37.04 and IEEE Std. C37.09. In particular: transfer general information from C37.04b.
- To update the references e.g. to the new IEEE Std C37.06.1 (Fast TRVs);
- To cover other applications e.g. systems with series capacitors;
- To develop the part on arc-circuit interaction;
- To develop the chapter on series reactors fault;
- To cover issues related to testing;
- To add a section on guidance for simulations of systems for TRV calculation.

Study Group meetings will continue in 2015 and 2016

PAR will submitted at the end of 2016

First WG meeting planned in Spring 2017.

Denis Dufournet

2015-04-27

**Roster\* Study Group Revision of IEEE C37.011 – Application Guide for TRV for HV Circuit-breakers**

<b>Name</b>	<b>Affiliation</b>	<b>Attend in St Pete 2015-04</b>	<b>Attend in San Diego 2015-09</b>
Denis Dufournet	Consultant (Alstom Grid)	X	
Joanne Hu	R&J Engineering Corporation	X	
Roy Alexander	RwA Engineering	X	
Mauricio Aristizabal	ABB	X	
Stan Billings	Mitsubishi Electric	X	
Anne Bosma	ABB Power Technologies	X	
Arben Bufi	HVB AE Power Systems	X	
Gilbert Carmona	Southern California Edison	X	
Lucas Collette	MEPPI	X	
Ken Edwards	BPA	X	
Helmut Heiermeier	ABB	X	
Victor Hermosillo	Alstom Grid	X	
Jim van de Ligt	CANA High Voltage Ltd		

<b>Name</b>	<b>Affiliation</b>	<b>Attend in St Pete 2015-04</b>	<b>Attend in San Diego 2015-09</b>
Hua Y. Liu	Southern California Edison	X	
Mirko Palazzo	ABB		
Jon Rogers	Siemens	X	
Rod Sauls	Alabama Power	X	
Carl Schuetz	ATC	X	
Jon Schumann	ATC	X	
Sushil Shinde	ABB	X	
Mike Skidmore	AEP	X	
Kirk Smith	Eaton	X	
Humayun Tariq	AEP	X	
John Webb	ABB		
Jan Weisker	Siemens	X	
Xi Zhu	GE	X	

\* Persons who expressed interest in membership and contribute either during meetings or by correspondence.